



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#15/2856  
B  
V. Brown  
3/21/03

In re Application of )  
Hans-Ulrich Krotil et al. )  
Serial No.: 09/869,789 ) Group:  
Filed: July 23, 2002 )  
Title: METHOD AND DEVICE FOR SIMULTANEOUSLY )  
DETERMINING THE ADHESION, FRICTION, AND )  
OTHER MATERIAL PROPERTIES OF A SAMPLE )

**PRELIMINARY AMENDMENT DELETING  
MULTIPLE DEPENDENT CLAIMS**

Assistant Commissioner of Patents  
Washington, DC 20231

Sir:

Prior to calculating the filing fee, please enter the following amendments to the application.

**IN THE CLAIMS**

Please amend claims 3, 5, 7, 9, 11, 13, 17, 19, 21, 23-25, and 27 as follows:

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3. Raster probe microscope according to claim 1,  
characterized by periodic raster-probe and/or sample oscillations.

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5. Raster probe microscope according to claim 3,  
characterized in that,  
the vertical oscillation of the raster probe (1) and/or of the sample (25) occurs with a first  
frequency of at least 10 Hz and a first amplitude of at least 1 nm.

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7. Raster probe microscope according to claim 5,  
characterized in that,  
the vertical oscillation of the raster probe (1) and/or of the sample (25) is additionally  
excited or modulated with a second frequency of at least 1 kHz and a second amplitude of  
at least 0.1 nm.

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9. Raster probe microscope according to claim 3,  
characterized in that,  
the second raster-probe and/or sample oscillation is a horizontal oscillation with a  
frequency of at least 500 Hz and an amplitude of at least 0.1 nm.

B5

11. Raster probe microscope according to claim 3,  
characterized by